

## MOS FIELD EFFECT TRANSISTOR 2SK3053

### SWITCHING N-CHANNEL POWER MOS FET INDUSTRIAL USE

### **DESCRIPTION**

The 2SK3053 is N-Channel MOS Field Effect Transistor designed for high current switching applications in consumer instruments.

### **ORDERING INFORMATION**

PART NUMBER	PACKAGE		
2SK3053	Isolated TO-220		

### **FEATURES**

• Low On-State Resistance

 $R_{DS(on)1} = 45~m\Omega~MAX.~(V_{GS} = 10~V,~I_{D} = 13~A)$   $R_{DS(on)2} = 70~m\Omega~MAX.~(V_{GS} = 4.0~V,~I_{D} = 13~A)$ 

- Low Ciss : Ciss = 790 pF TYP.
- Built-in Gate Protection Diode
- Isolated TO-220 package

(Isolated TO-220)



### ABSOLUTE MAXIMUM RATINGS (TA = 25 °C)

Drain to Source Voltage	VDSS	60	V
Gate to Source Voltage	VGSS(AC)	±20	V
Gate to Source Voltage	VGSS(DC)	+20, -10	V
Drain Current (DC)	I <sub>D(DC)</sub>	±25	Α
Drain Current (Pulse) Note1	D(pulse)	±75	Α
Total Power Dissipation (Tc = 25°C)	PT	30	W
Total Power Dissipation (T <sub>A</sub> = 25°C)	PT	2.0	W
Channel Temperature	$T_ch$	150	°C
Storage Temperature	Tstg	-55 to +150	°C
Single Avalanche Current Note2	las	12.5	Α
Single Avalanche Energy Note2	Eas	15.6	mJ

**Notes 1.** PW  $\leq$  10  $\mu$ s, Duty cycle  $\leq$  1 %

2. Starting Tch = 25 °C, RG = 25  $\Omega$ , VGS = 20 V  $\rightarrow$  0 V

### THERMAL RESISTANCE

Channel to Case	Rth(ch-C)	4.17	°C/W	
Channel to Ambient	Rth(ch-A)	62.5	°C/W	

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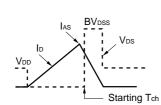


### **ELECTRICAL CHARACTERISTICS (TA = 25 °C)**

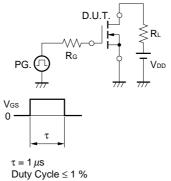
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CHARACTERISTICS	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
Drain to Source On-state Resistance	RDS(on)1	V <sub>G</sub> S = 10 V, I <sub>D</sub> = 13 A		28	45	mΩ
	RDS(on)2	Vgs = 4.0 V, ID = 13 A		46	70	mΩ
Gate to Source Cut-off Voltage	V <sub>GS(off)</sub>	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 1 mA	1.0	1.6	2.0	٧
Forward Transfer Admittance	<b>y</b> fs	Vps = 10 V, lp = 13 A	8.0	16		S
Drain Leakage Current	Inss	Vps = 60 V, Vgs = 0 V			10	μΑ
Gate to Source Leakage Current	lgss	Vgs = ±20 V, Vps = 0 V			±10	μΑ
Input Capacitance	Ciss	V <sub>DS</sub> = 10 V		790		pF
Output Capacitance	Coss	V <sub>G</sub> s = 0 V		240		pF
Reverse Transfer Capacitance	Crss	f = 1 MHz		100		pF
Turn-on Delay Time	td(on)	ID = 13 A		20		ns
Rise Time	<b>t</b> r	V <sub>GS(on)</sub> = 10 V		200		ns
Turn-off Delay Time	td(off)	VDD = 30 V		65		ns
Fall Time	<b>t</b> f	$R_G = 10 \Omega$		95		ns
Total Gate Charge	Q <sub>G</sub>	I <sub>D</sub> = 25 A		20		nC
Gate to Source Charge	Qgs	V <sub>DD</sub> = 48 V		3.0		nC
Gate to Drain Charge	Q <sub>GD</sub>	V <sub>GS(on)</sub> = 10 V		6.5		nC
Body Diode Forward Voltage	V <sub>F(S-D)</sub>	IF = 25 A, VGS = 0 V		1.0		V
Reverse Recovery Time	trr	IF = 25 A, VGS = 0 V		40		ns
Reverse Recovery Charge	Qrr	di/dt = 100 A/μs		45		nC

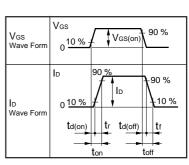
### **TEST CIRCUIT 1 AVALANCHE CAPABILITY**

# $R_{G} = 25 \Omega$ $P_{G}$ $V_{GS} = 20 \rightarrow 0 \text{ V}$ $P_{M}$ $P_{M}$ $P_{M}$ $P_{M}$ $P_{M}$

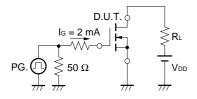


### TEST CIRCUIT 2 SWITCHING TIME



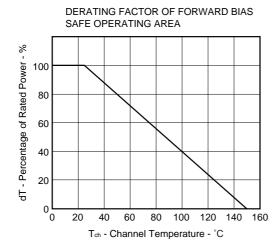


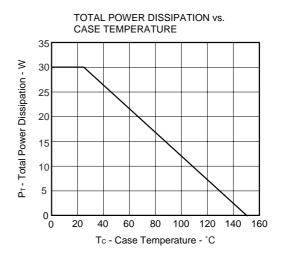
### **TEST CIRCUIT 3 GATE CHARGE**

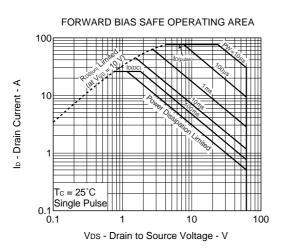




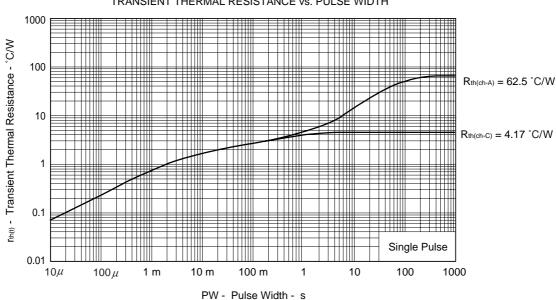
### TYPICAL CHARACTERISTICS (TA = 25 °C)





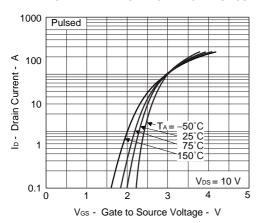


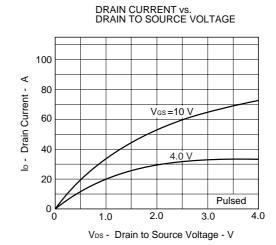
### TRANSIENT THERMAL RESISTANCE vs. PULSE WIDTH



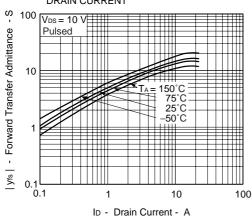
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#### FORWARD TRANSFER CHARACTERISTICS

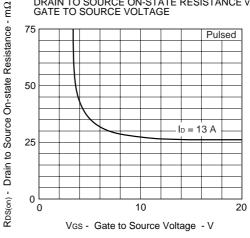




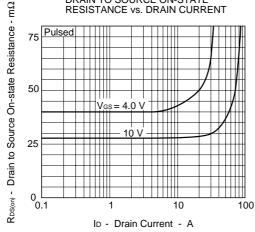
FORWARD TRANSFER ADMITTANCE vs. DRAIN CURRENT



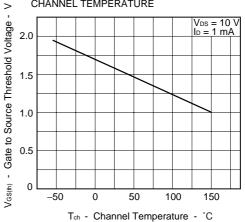
DRAIN TO SOURCE ON-STATE RESISTANCE vs. GATE TO SOURCE VOLTAGE



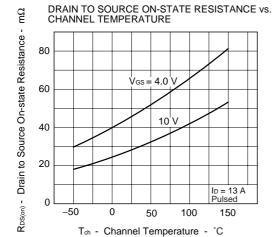
DRAIN TO SOURCE ON-STATE

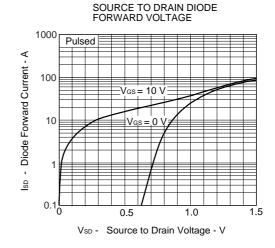


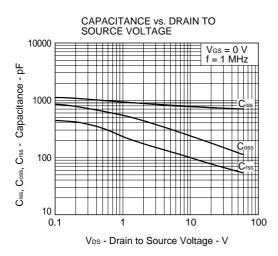
GATE TO SOURCE THRESHOLD VOLTAGE vs. CHANNEL TEMPERATURE

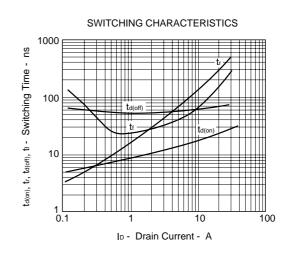


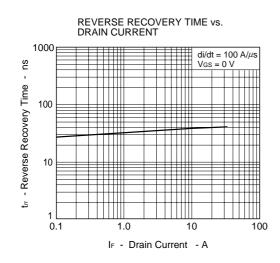


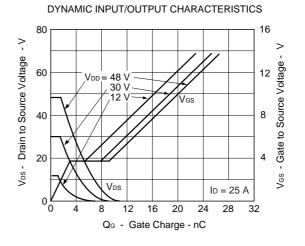


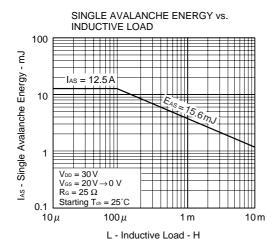


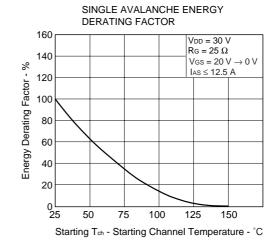








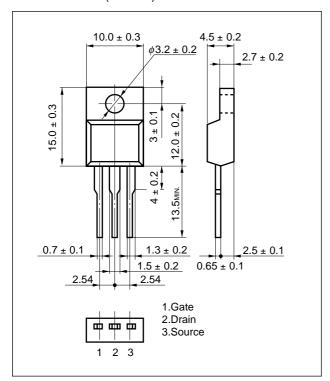




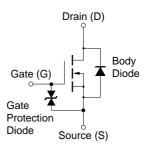


### **PACKAGE DRAWING**

Isolated TO-220 (MP-45F)



### **EQUIVALENT CIRCUIT**



- ★ Remark 1. This product is designed for consumer application and isn't suitable for automotive application.
  - 2. The diode connected between the gate and source of the transistor serves as a protector against ESD. When this device actually used, an additional protection circuit is externally required if a voltage exceeding the rated voltage may be applied to this device.

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